

**Search Notes**

Application/Control No.

10/654,769

Examiner

Anthony Weier

Applicant(s)/Patent under  
Reexamination

AKASHE ET AL.

Art Unit

1761

**SEARCHED**

Class	Subclass	Date	Examiner
updated	previous search	11/29/2005	AW

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR